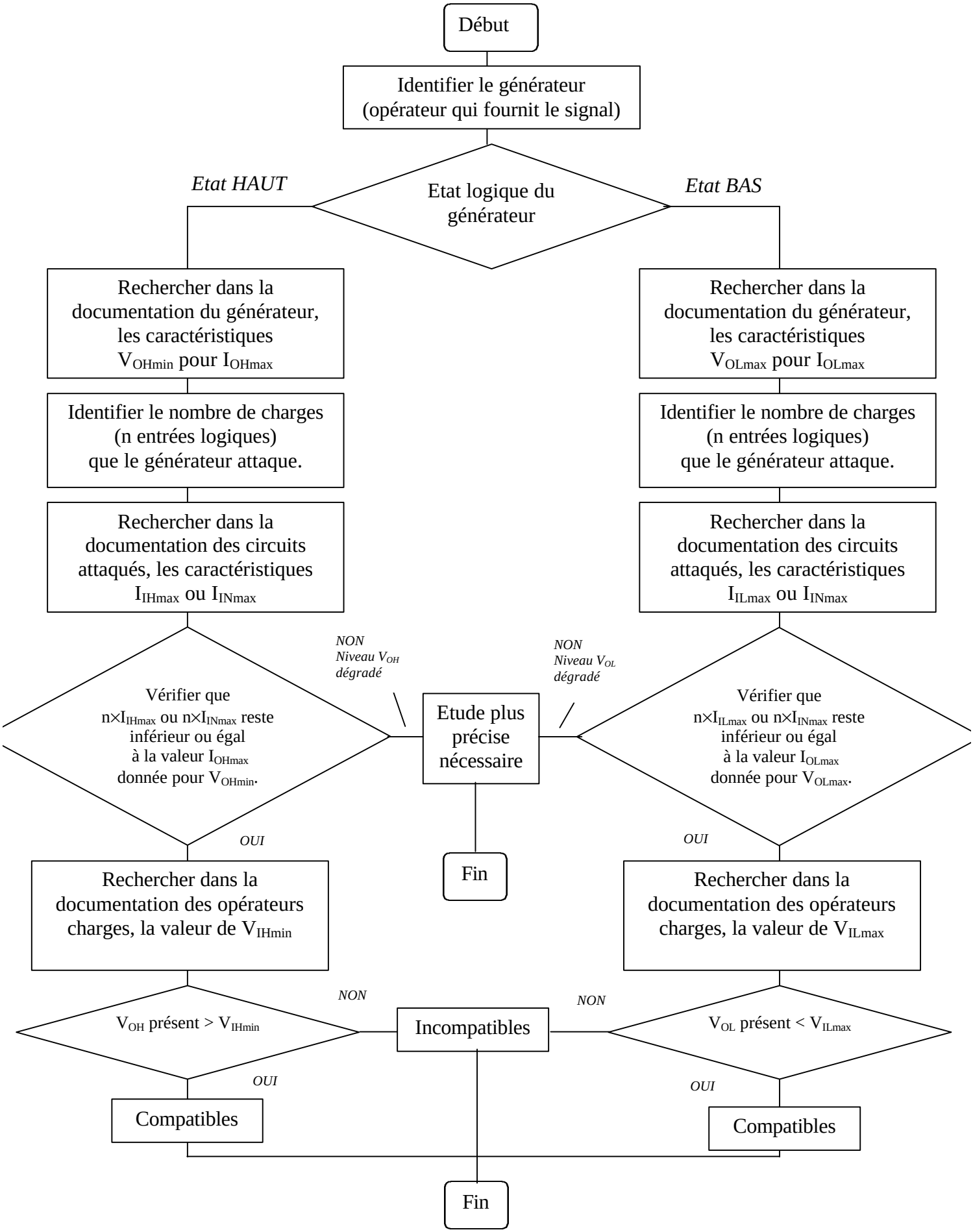
Laurent LUBRANO 2000

Vérification de la compatibilité technologique entre circuits intégrés logiques